# **MOSFET, N-Channel Shielded Gate, POWERTRENCH®**

**80 V**, 116 A, 4.2 mΩ

### **General Description**

This N-Channel MV MOSFET is produced using ON Semiconductor's advanced POWERTRENCH® process that incorporates Shielded Gate technology. This process has been optimized to minimise on-state resistance and yet maintain superior switching performance with best in class soft body diode.

### **Features**

- Shielded Gate MOSFET Technology
- Max  $r_{DS(on)} = 4.2 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 37 \text{ A}$
- Max  $r_{DS(on)} = 6.1 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 29 \text{ A}$
- 50% Lower Qrr than Other MOSFET Suppliers
- Lowers Switching Noise/EMI
- MSL1 Robust Package Design
- 100% UIL Tested
- RoHS Compliant

# **Typical Applications**

- Primary DC-DC MOSFET
- Synchronous Rectifier in DC-DC and AC-DC
- Motor Drive
- Solar

# MOSFET MAXIMUM RATINGS (T<sub>A</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Ratings	Unit
V <sub>DS</sub>	Drain to Source Voltage	80	٧
V <sub>GS</sub>	Gate to Source Voltage	±20	٧
I <sub>D</sub>	Drain Current – Continuous $T_C = 25^{\circ}C$ (Note 5)	116	Α
	<ul><li>Continuous T<sub>C</sub> = 100°C (Note 5)</li></ul>	73	
	− Continuous T <sub>A</sub> = 25°C (Note 1a)	17	
	- Pulsed (Note 4)	633	
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 3)	384	mJ
P <sub>D</sub>	Power dissipation T <sub>C</sub> = 25°C	113.6	W
	Power dissipation T <sub>A</sub> = 25°C (Note 1a)	2.5	
T <sub>J,</sub> T <sub>STG</sub>	Operating and Storage Junction Temperature Range	–55 to +150	°C

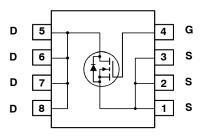
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



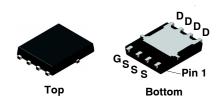
# ON Semiconductor®

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# **ELECTRICAL CONNECTION**



**N-Channel MOSFET** 



Power 56 (PQFN8 5x6) CASE 483AE

### **MARKING DIAGRAM**

\$Y&Z&3&K **FDMS** 4D5N08LC

\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Numeric Date Code &K = Lot Code

FDMS4D5N08LC = Specific Device Code

### ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

### THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case	1.1	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	

# PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Shipping <sup>†</sup>
FDMS4D5N08LC	FDMS4D5N08LC	PQFN8 5×6 (Pb-Free/Halogen Free)	3000 Units/ Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRIC	AL CHARACTERISTICS (T <sub>J</sub> = 25°C unle	ess otherwise noted)				
Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
OFF CHARA	CTERISTICS					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	80			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25°C		66		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 64 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSS</sub>	Gate-to-Source Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±100	nA
ON CHARAC	CTERISTICS					
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 210 μA	1.0	1.4	2.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 210 μA, referenced to 25°C		-5.1		mV/°C
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 37 A		3.2	4.2	mΩ
		V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 29 A		4.5	6.1	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 37 A, T <sub>J</sub> = 125°C		5.7	7.5	
9FS	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 37 A		135		S
DYNAMIC C	HARACTERISTICS					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V, f = 1MHz		3640	5100	
C <sub>oss</sub>	Output Capacitance			834	1170	рF
C <sub>rss</sub>	Reverse Transfer Capacitance			39	65	
$R_g$	Gate Resistance		0.1	0.6	1.1	Ω
SWITCHING	CHARACTERISTICS					
td <sub>(on)</sub>	Turn – On Delay Time	V <sub>DD</sub> = 40 V, I <sub>D</sub> = 37 A,		13	23	ns
t <sub>r</sub>	Rise Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		19	34	
t <sub>D(off)</sub>	Turn – Off Delay Time			59	94	
t <sub>f</sub>	Fall Time			17	30	
Qg	Total Gate Charge	V <sub>GS</sub> = 0V to 10 V		51	71	nC
Qg	Total Gate Charge	V <sub>GS</sub> = 0V to 4.5 V		24	34	
Q <sub>gs</sub>	Gate to Source Charge	V <sub>DD</sub> = 40 V, i <sub>D</sub> = 37 A		8		
$Q_{gd}$	Gate to Drain "Miller" Charge			6		
Q <sub>oss</sub>	Output Charge	V <sub>DD</sub> = 40 V, V <sub>GS</sub> = 0 V		51		nC
Q <sub>sync</sub>	Total Gate Charge Sync.	V <sub>DS</sub> = 0 V, I <sub>D</sub> = 37 A		46		

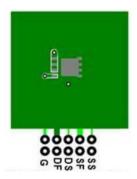
### ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25°C unless otherwise noted) (continued)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit	
DRAIN-SOU	DRAIN-SOURCE DIODE CHARACTERISTICS						
$V_{SD}$	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.1 A (Note 2)		0.7	1.2	V	
		V <sub>GS</sub> = 0 V, I <sub>S</sub> = 37 A (Note 2)		0.8	1.3		
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 18 A, di/dt = 300 A/μs		22	36	ns	
Q <sub>rr</sub>	Reverse Recovery Charge	1		38	61	nC	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 18 A, di/dt = 1000 A/μs		17	27	ns	
Q <sub>rr</sub>	Reverse Recovery Charge			82	132	nC	

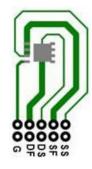
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

### NOTES:

 R<sub>θ,JA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 × 1.5 in. board of FR-4 material. R<sub>θCA</sub> is determined by the user's board design.



 a) 50°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b) 125°C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.
- E<sub>AS</sub> of 384 mJ is based on starting T<sub>J</sub> = 25°C; N-ch: L = 3 mH, I<sub>AS</sub> = 16 A, V<sub>DD</sub> = 72 V, V<sub>GS</sub> = 10 V. 100% tested at L = 0.1 mH, I<sub>AS</sub> = 41 A, V<sub>GS</sub> = 10 V.
- 4. Pulsed  $I_D$  please refer to Figure 11 SOA graph for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

# TYPICAL CHARACTERISTICS T<sub>J</sub> = 25°C unless otherwise noted

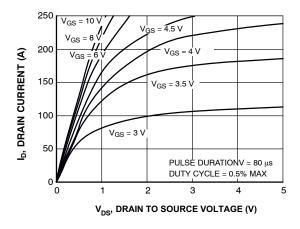


Figure 1. On Region Characteristics

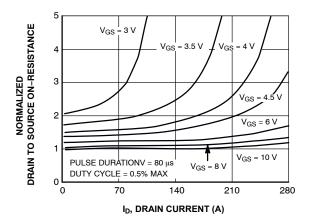


Figure 2. Normalized On–Resistance vs. Drain Current and Gate Voltage

# TYPICAL CHARACTERISTICS T<sub>J</sub> = 25°C unless otherwise noted (continued)

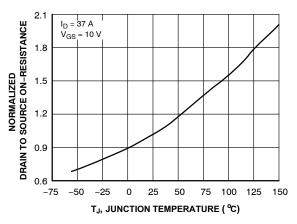


Figure 3. Normalized On Resistance vs. Junction Temperature

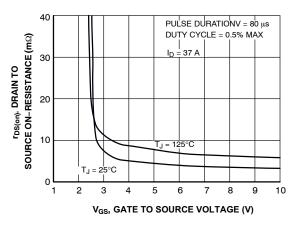


Figure 4. On-Resistance vs. Gate to Source Voltage

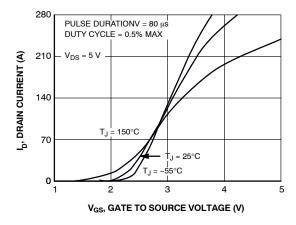


Figure 5. Transfer Characteristics

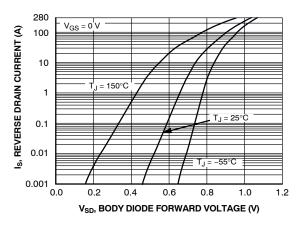


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

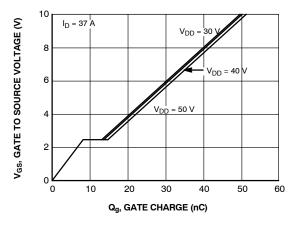


Figure 7. Gate Charge Characteristics

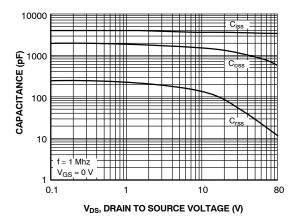


Figure 8. Capacitance vs. Drain to Source Voltage

# TYPICAL CHARACTERISTICS T<sub>J</sub> = 25°C unless otherwise noted (continued)

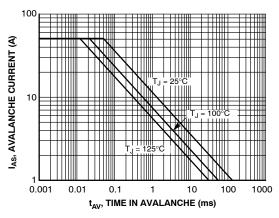


Figure 9. Unclamped Inductive Switching Capability

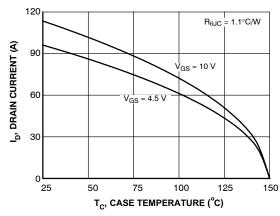


Figure 10. Maximum Continous Drain Current vs. Case Temperature

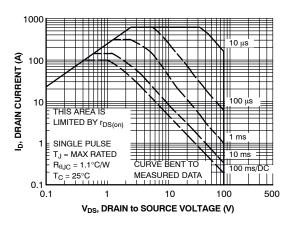


Figure 11. Unclamped Inductive Switching Capability

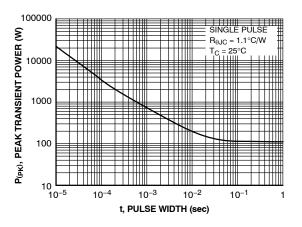


Figure 12. Maximum Continuous Drain Current vs. Case Temperature

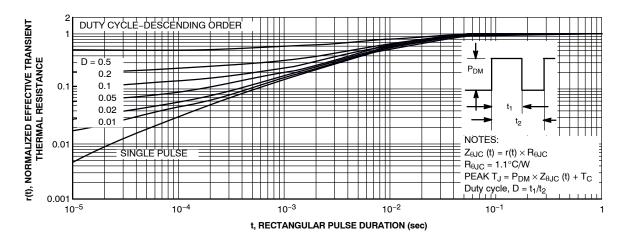
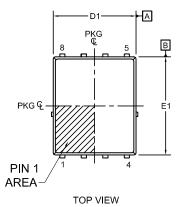


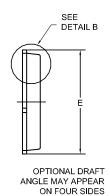
Figure 13. Junction-to-Case Transient Thermal Response Curve

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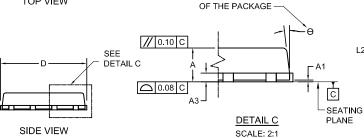
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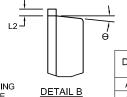




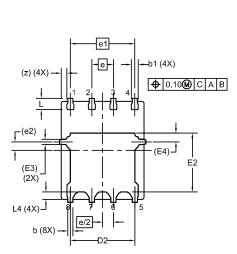
### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. COPLANARITY APPLIES TO THE EXPOSED PADS AS WELL AS THE TERMINALS.
- 4. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.
- 5. SEATING PLANE IS DEFINED BY THE TERMINALS. "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.
- 6. IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.

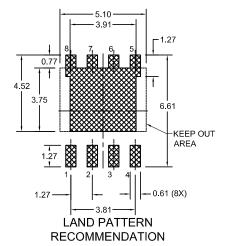




SCALE: 2:1



**BOTTOM VIEW** 



\*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

DIM	M	IILLIMET	ERS	
DIIVI	MIN.	NOM.	MAX.	
Α	0.90	1.00	1.10	
A1	0.00	-	0.05	
b	0.21	0.31	0.41	
b1	0.31	0.41	0.51	
A3	0.15	0.25	0.35	
D	4.90	5.00	5.20	
D1	4.80	4.90	5.00	
D2	3.61	3.82	3.96	
Е	6.05	6.15	6.25	
E1	5.70	5.80	5.90	
E2	3.38	3.48	3.78	
E3	(	0.30 REF		
E4	(	0.52 REF		
е	,	1.27 BSC	;	
e/2	(	0.635 BS	С	
e1	;	3.81 BSC	;	
e2	(	0.50 REF		
L	0.51	0.66	0.76	
L2	0.05	0.18	0.30	
L4	0.34	0.44	0.54	
Z	0.34 REF			
θ	0°	-	12°	

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DESCRIPTION:	PQFN8 5X6, 1.27P	•	PAGE 1 OF 1	

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